

# Characterization and Electronic Structure of LaAlO<sub>3</sub>/LaVO<sub>3</sub> Interfaces by Hard X-ray Photoelectron Spectroscopy

Hiroki Wadati<sup>1</sup>, Yasushi Hotta<sup>2</sup>, Masaru Takizawa<sup>1</sup>, Atsushi Fujimori<sup>1</sup>,  
Yasutaka Takata<sup>3</sup>, Koji Horiba<sup>3</sup>, Masaharu Matsunami<sup>3</sup>, Shik Shin<sup>3</sup>,  
Makina Yabashi<sup>3,4</sup>, Kenji Tamasaku<sup>3</sup>, Yoshinori Nishino<sup>3</sup>, Daigo Miwa<sup>3</sup>,  
Tetsuya Ishikawa<sup>3,4</sup>, Tomofumi Susaki<sup>2</sup>, Harold Y. Hwang<sup>2</sup>

<sup>1</sup>Department of Physics and Department of Complexity Science and Engineering,  
University of Tokyo, 5-1-5 Kashiwanoha, Kashiwa, Chiba 277-8561, Japan

<sup>2</sup>Department of Advanced Materials Science, University of Tokyo,  
5-1-5 Kashiwanoha, Kashiwa, Chiba 277-8561, Japan

<sup>3</sup>RIKEN/SPring-8, 1-1-1 Kouto, Mikazuki-cho, Sayo-gun, Hyogo 679-5148, Japan

<sup>4</sup>JASRI/SPring-8, 1-1-1 Kouto, Mikazuki-cho, Sayo-gun, Hyogo 679-5198, Japan

Due to the recent development in oxide thin film fabrication, atomically controlled heterostructures of transition-metal oxides have become available. Novel electronic structures such as the metallic state between Mott and band insulators [1] are expected to appear at the interfaces of such structures. In this work, we have performed a photoemission study of interfaces between a band insulator LaAlO<sub>3</sub> (LAO) and a Mott insulator LaVO<sub>3</sub> (LVO) using hard x rays (~ 8 keV) at BL-29XU of SPring-8. We have studied LAO (3ML)/LVO (50ML), LAO (3ML)/LVO (3ML)/LAO (30ML), and thick LVO (50ML) grown on SrTiO<sub>3</sub> (STO) substrates.

A Mott-Hubbard gap of LVO remained open at the interface between LAO and LVO as shown in Fig.1, indicating that this interface was insulating unlike the LaTiO<sub>3</sub>/STO interfaces [1]. The value of the gap of LAO(3ML)/LVO(50ML) was almost the same (~ 100 meV) as that of thick LVO(50ML), while that of LAO(3ML)/LVO(3ML) was much larger (~ 400 meV) due to the energy shift of V 3d band. We found from V 1s and 2p core-level photoemission spectra that the valence of V in LVO were partially converted from V<sup>3+</sup> to V<sup>4+</sup> and V<sup>5+</sup> at the interface.

[1] A. Ohtomo *et al.*, Nature **419**, 378 (2002).

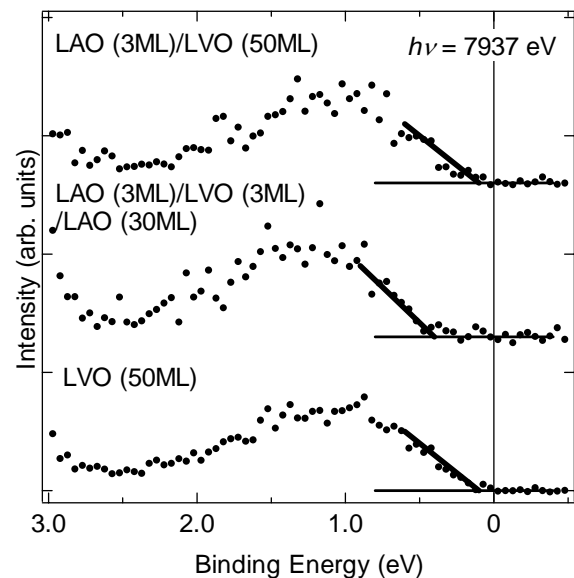


Fig. 1: V 3d band photoemission spectra of LaAlO<sub>3</sub>/LaVO<sub>3</sub> heterostructures and a LaVO<sub>3</sub> thin film.